

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L7	2	(VARSHNEY.in. or CHANDRASEKAR.in.) and glitch	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:12
L8	38	(VARSHNEY.in. or CHANDRASEKAR.in.) and noise	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:12
L9	2	(VARSHNEY.in. or CHANDRASEKAR.in.) and (noise with immunity)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:13
L10	684	glitch and (noise with immunity)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:56
L11	151	((worst or pessimistic) with bit) and 10	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:51
L12	246	(curve or plot or graph) with (failure or fail\$3 or fall\$3) with (glitch or noise)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:26
L13	5	(curve or plot or graph) with (failure or fail\$3 or fall\$3) with (glitch or noise) with immunity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:46
L14	1	11 and 13	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:45
L15	6	(curve or plot or graph) with (failure or fail\$3 or fall\$3) with (glitch or noise) same immunity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:53
L16	15	(curve or plot or graph) with (failure or fail\$3 or fall\$3) with (glitch or noise) and immunity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:50
L17	18	(curve or plot or graph) same (failure or fail\$3 or fall\$3) same (glitch or noise) same immunity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:51

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L18	1	17 and 11	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:51
L19	159	((worst or pessimistic) same bit) and 10	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:52
L20	1	17 and 19	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:52
L21	263	((worst or pessimistic) and bit) and 10	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:52
L22	1	17 and 21	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:52
L23	4	((curve or plot or graph) and (failure or fail\$3 or fall\$3) and (glitch or noise) and immunity).clm.	US-PGPUB	OR	ON	2007/07/05 14:54
L24	1	((worst or pessimistic) and bit).clm. and 23	US-PGPUB	OR	ON	2007/07/05 14:55
L25	1	(worst or pessimistic).clm. and 23	US-PGPUB	OR	ON	2007/07/05 14:57
L26	1	bit.clm. and 23	US-PGPUB	OR	ON	2007/07/05 14:55
L27	4	(glitch and noise and immunity).clm.	US-PGPUB	OR	ON	2007/07/05 14:57
L28	1	(worst or pessimistic).clm. and 27	US-PGPUB	OR	ON	2007/07/05 14:58
L29	3	23 and 27	US-PGPUB	OR	ON	2007/07/05 14:57
L30	1	(worst or pessimistic).clm. and 29	US-PGPUB	OR	ON	2007/07/05 14:58
L31	2	("6836873").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2007/07/05 15:21
L32	0	("7760498").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2007/07/05 15:27
L33	2843	716/4.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 15:53
L34	2164	716/5.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 16:26
			US-PGPUB; USPAT; EPO; JPO; DERWENT			

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L35	1747	716/6.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 17:06
L36	1239	703/14.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 17:06

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Results for "((immunity and noise and glitch and (worst or pessimistic))<in>metadata)"

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» Key

IEEE JNL	IEEE Journal or Magazine
IET JNL	IET Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IET CNF	IET Conference Proceeding
IEEE STD	IEEE Standard

- ☐ 1. **Aggressor aware repeater circuits for improving on-chip bus performance and robustness**
Katoch, A.; Jain, S.K.; Meijer, M.;
[Solid-State Circuits Conference, 2003. ESSCIRC '03. Proceedings of the 29th European](#)
16-18 Sept. 2003 Page(s):261 - 264
Digital Object Identifier 10.1109/ESSCIRC.2003.1257122
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Enter keywords or phrases, select fields, and select operators

<input type="text"/>	in All Fields	<input type="button" value="v"/>
AND <input type="button" value="v"/>	<input type="text"/>	in All Fields <input type="button" value="v"/>
AND <input type="button" value="v"/>	<input type="text"/>	in All Fields <input type="button" value="v"/>

» Note: If you use all three search boxes, the entries in the first two boxes take precedence over the entry in the third box.

**OPTION 2**

Enter keywords, phrases, or a Boolean expression

immunity and noise and glitch and (worst or pessimistic)	<input type="button" value="v"/>
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» Note: You may use the search operators <and> or <or> without the start and end brackets <>.

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